

FORM PTO-1449 (REV. 7-80)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. TI-14124D.6		SERIAL NO. div. of 10/649,274	
LIST OF DOCUMENTS CITED BY APPLICANT <i>(Use several sheets if necessary)</i>				APPLICANT Lee D. Whetsel			
				FILING DATE October 22, 2003		GROUP TBD 2133	
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
cb		EP 0,310,152	4/5/1989	Europe	G01	R31/28	X
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EXAMINER C. Brutt				DATE CONSIDERED 4-25-08			
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EXAMINER C. Batt		DATE CONSIDERED 4-25-05			
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